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APPLICA	Dominique Barthel \$\int_{70}\$ Method for testing integrated circuits with memory element access								
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WARNI The Inform	nation disclosed	herein may be res	stricted. Unauthorized	d disclosure may be	prohibited by the	United States C	ode Title 35	5, Sections 122, 181 and 368	
ossessio	on outside the U.	S. Patent & Trader	nark Office is restricte	d to authorized em	Ployees and contra FILED WITH	ctors only.		TFICHE CD-RO	J